

- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

Product Summary



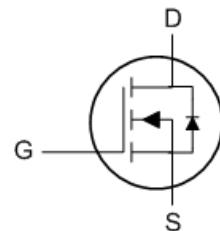
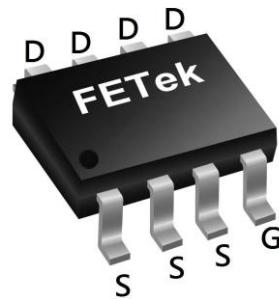
BVDSS	RDS(ON)	ID
80V	7mΩ	17.5A

Description

The FKS8048 is the high cell density trenched N-ch MOSFETs, which provide excellent RDS(ON) and gate charge for most of the synchronous rectification applications.

The FKS8048 meet the RoHS and Halogen-Free compliant product requirement, 100% EAS guaranteed with full function reliability approved.

SOP8 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	80	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current ¹	17.5	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current ¹	14	A
I_{DM}	Pulsed Drain Current ²	68	A
EAS	Single Pulse Avalanche Energy ³	57.8	mJ
I_{AS}	Avalanche Current	34	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation ⁴	3.1	W
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹ ($t \leq 10s$)	---	40	°C/W
	Thermal Resistance Junction-Ambient ¹	---	75	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	---	24	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	80	---	---	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=15\text{A}$	---	4.8	7	$\text{m}\Omega$
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=4.5\text{V}$, $I_D=10\text{A}$	---	6.7	9	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	1.2	---	2.3	V
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=64\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	uA
		$V_{\text{DS}}=64\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_D=15\text{A}$	---	75	---	S
R_g	Gate Resistance	$V_{\text{DS}}=0\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	0.5	---	Ω
Q_g	Total Gate Charge (10V)	$V_{\text{DS}}=40\text{V}$, $V_{\text{GS}}=10\text{V}$, $I_D=15\text{A}$	---	40	---	nC
Q_{gs}	Gate-Source Charge		---	7.2	---	
Q_{gd}	Gate-Drain Charge		---	6.5	---	
$\text{T}_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=40\text{V}$, $V_{\text{GS}}=10\text{V}$, $R_g=3\Omega$, $I_D=15\text{A}$	---	8.3	---	ns
T_r	Rise Time		---	4.2	---	
$\text{T}_{\text{d(off)}}$	Turn-Off Delay Time		---	36	---	
T_f	Fall Time		---	6.9	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=40\text{V}$, $V_{\text{GS}}=0\text{V}$, $f=1\text{MHz}$	---	2860	---	pF
C_{oss}	Output Capacitance		---	410	---	
Crss	Reverse Transfer Capacitance		---	38	---	

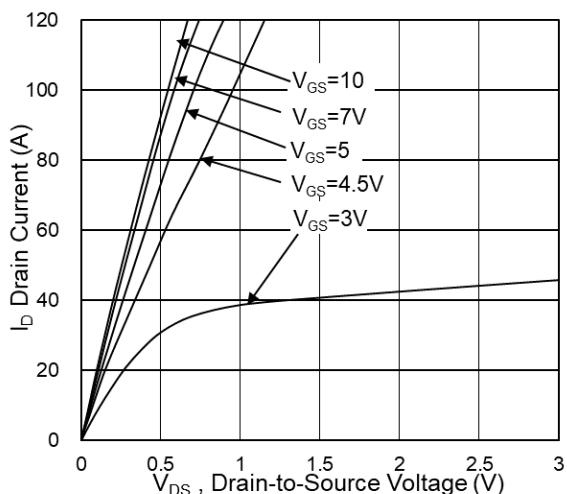
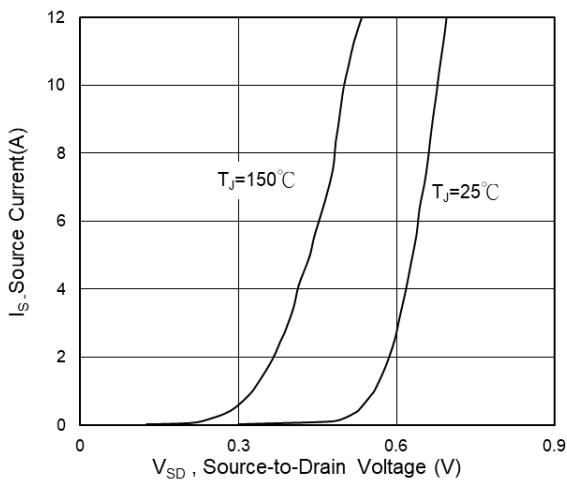
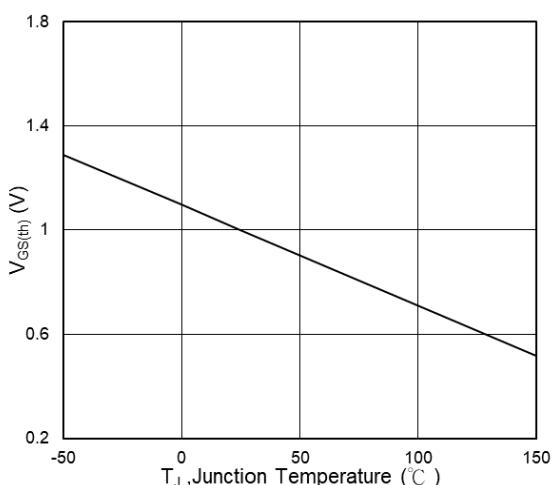
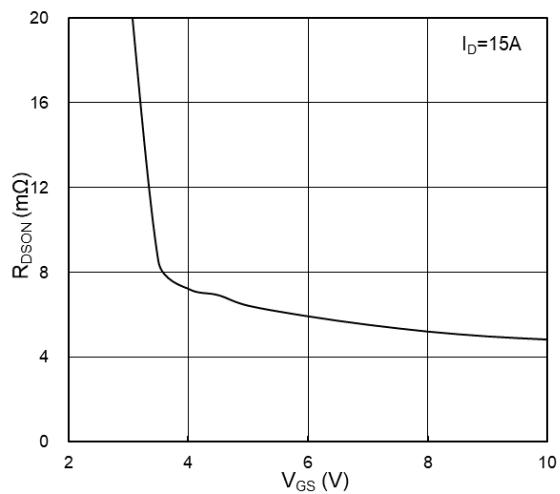
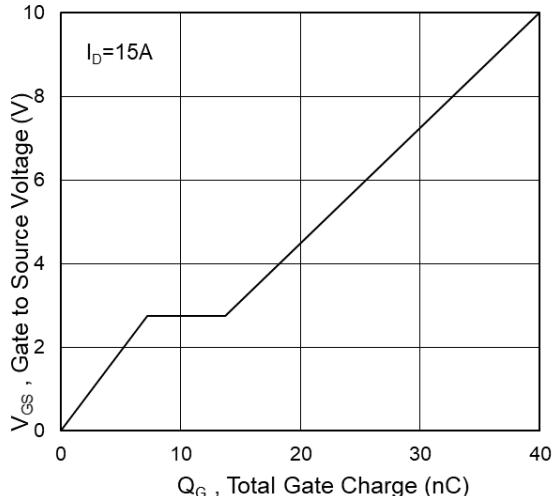
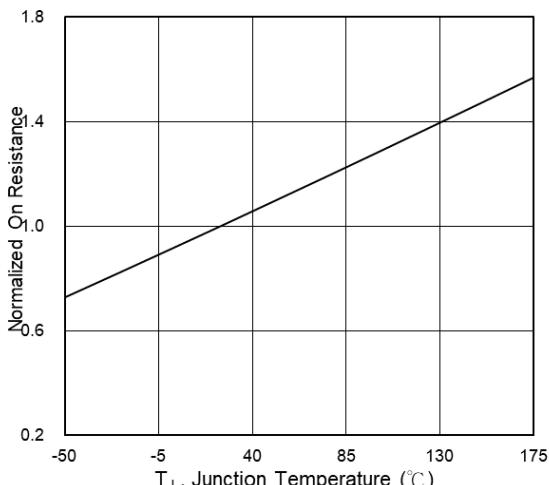
Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,5}	$V_G=V_D=0\text{V}$, Force Current	---	---	48	A
V_{SD}	Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}$, $\text{I}_s=A$, $T_J=25^\circ\text{C}$	---	0.77	1.0	V
t_{rr}	Reverse Recovery Time	$\text{I}_F=15\text{A}$, $d\text{I}/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$	---	23	---	nS
Q_{rr}	Reverse Recovery Charge		---	75	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=25\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=0.1\text{mH}$, $\text{I}_{\text{AS}}=34\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics


Fig.1 Typical Output Characteristics

Fig.3 Source Drain Forward Characteristics

Fig.5 Normalized $V_{GS(th)}$ vs T_J

Fig.2 On-Resistance vs G-S Voltage

Fig.4 Gate-Charge Characteristics

Fig.6 Normalized R_{DSON} vs T_J

